

Search Notes

Application/Control No.

10/757,269

Examiner

Vincent Lai

Applicant(s)/Patent under
Reexamination

DEWITT ET AL.

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
712	227	4/21/2006	VL
712	229	4/21/2006	VL
712	243	4/21/2006	VL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Look at patent # 6,233,679 & 5,887,159	4/21/2006	VL
Forward & backward searches on patents above	4/22/2006	VL
Search terms: count metric, threshold, counters, instruction cache, indicator, tag, ID, bit, subroutine, function	4/22/2006	VL
Search terms (con): input/output, module	4/22/2006	VL